



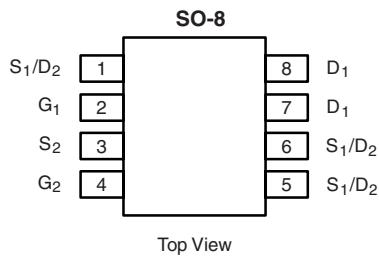
Dual N-Channel 25-V (D-S) MOSFET with Schottky Diode

PRODUCT SUMMARY

	V_{DS} (V)	$r_{DS(on)}$ (Ω)	I_D (A) ^{a, e}	Q_g (Typ)
Channel-1	25	0.023 at $V_{GS} = 10$ V	8.0	5.5
		0.028 at $V_{GS} = 4.5$ V	8.0	
Channel-2	25	0.023 at $V_{GS} = 10$ V	8.0	5.5
		0.028 at $V_{GS} = 4.5$ V	8.0	

SCHOTTKY PRODUCT SUMMARY

V_{DS} (V)	V_{SD} (V) Diode Forward Voltage	I_F (A) ^a
25	0.43 V at 1.0 A	2.3



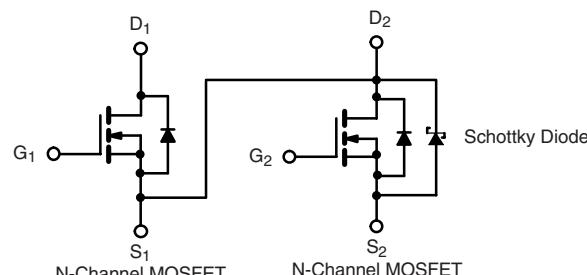
FEATURES

- TrenchFET® Power MOSFET
- PWM Optimized

RoHS
COMPLIANT

APPLICATIONS

- Synchronous Buck Converter
- Game Machine
- Notebook



Ordering Information: Si4670DY-T1-E3 (Lead (Pb)-free)

ABSOLUTE MAXIMUM RATINGS $T_A = 25$ °C, unless otherwise noted

Parameter	Symbol	Channel-1	Channel-2	Unit
Drain-Source Voltage	V_{DS}	25	25	V
Gate-Source Voltage	V_{GS}	± 16	± 16	
Continuous Drain Current ($T_J = 150$ °C)	I_D	8.0 ^e	8.0 ^e	A
		7	7	
		7 ^{b, c}	7 ^{b, c}	
		5.6 ^{b, c}	5.6 ^{b, c}	
Pulsed Drain Current (10 μ s Pulse Width)	I_{DM}	30	30	
Source-Drain Current Diode Current	I_S	2.3	2.3	
		1.5 ^{b, c}	1.5 ^{b, c}	
Maximum Power Dissipation	P_D	2.8	2.8	W
		1.8	1.8	
		1.8 ^{b, c}	1.8 ^{b, c}	
		1.1 ^{b, c}	1.1 ^{b, c}	
Operating Junction and Storage Temperature Range	T_J, T_{stg}	- 55 to 150		°C

THERMAL RESISTANCE RATINGS

Parameter	Symbol	Channel-1		Channel-2		Unit
		Typ	Max	Typ	Max	
Maximum Junction-to-Ambient ^{b, d}	R_{thJA}	57	70	57	70	
Maximum Junction-to-Foot (Drain)	R_{thJF}	36	44	36	44	°C/W

Notes:

- a. Based on $T_C = 25$ °C.
- b. Surface Mounted on 1" x 1" FR4 Board.
- c. $t = 10$ s.
- d. Maximum under Steady State conditions is 110 °C/W (Channel-1 and Channel-2).
- e. Package Limited.

SPECIFICATIONS $T_J = 25^\circ\text{C}$, unless otherwise noted

Parameter	Symbol	Test Conditions	Min	Typ ^a	Max	Unit	
Static							
Drain-Source Breakdown Voltage	V_{DS}	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	Ch-1	25		V	
		$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	Ch-2	25			
V_{DS} Temperature Coefficient	$\Delta V_{DS}/T_J$	$I_D = 250 \mu\text{A}$	Ch-1		25	mV/ $^\circ\text{C}$	
$V_{GS(\text{th})}$ Temperature Coefficient	$\Delta V_{GS(\text{th})}/T_J$	$I_D = 250 \mu\text{A}$	Ch-1		- 4.7		
Gate Threshold Voltage	$V_{GS(\text{th})}$	$V_{DS} = V_{GS}, I_D = 250 \mu\text{A}$	Ch-1	1	2.2	V	
		$V_{DS} = V_{GS}, I_D = 250 \mu\text{A}$	Ch-2	1	2.2		
Gate-Body Leakage	I_{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 16 \text{ V}$	Ch-1		100	nA	
		$V_{DS} = 0 \text{ V}, V_{GS} = \pm 16 \text{ V}$	Ch-2		100		
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = 25 \text{ V}, V_{GS} = 0 \text{ V}$	Ch-1		0.001	mA	
		$V_{DS} = 25 \text{ V}, V_{GS} = 0 \text{ V}$	Ch-2		0.07		
		$V_{DS} = 25 \text{ V}, V_{GS} = 0 \text{ V}, T_J = 100^\circ\text{C}$	Ch-1		0.025		
		$V_{DS} = 25 \text{ V}, V_{GS} = 0 \text{ V}, T_J = 100^\circ\text{C}$	Ch-2		5		
On-State Drain Current ^b	$I_{D(on)}$	$V_{DS} \geq 5 \text{ V}, V_{GS} = 10 \text{ V}$	Ch-1	20		A	
		$V_{DS} \geq 5 \text{ V}, V_{GS} = 10 \text{ V}$	Ch-2	20			
Drain-Source On-State Resistance ^b	$r_{DS(on)}$	$V_{GS} = 10 \text{ V}, I_D = 7 \text{ A}$	Ch-1		0.019	Ω	
		$V_{GS} = 10 \text{ V}, I_D = 7 \text{ A}$	Ch-2		0.019		
		$V_{GS} = 4.5 \text{ V}, I_D = 6.3 \text{ A}$	Ch-1		0.023		
		$V_{GS} = 4.5 \text{ V}, I_D = 6.3 \text{ A}$	Ch-2		0.023		
Forward Transconductance ^b	g_{fs}	$V_{DS} = 10 \text{ V}, I_D = 7 \text{ A}$	Ch-1		23	S	
		$V_{DS} = 10 \text{ V}, I_D = 7 \text{ A}$	Ch-2		23		
Dynamic^a							
Input Capacitance	C_{iss}	Channel-1 $V_{DS} = 13 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$	Ch-1		680	pF	
			Ch-2		680		
Output Capacitance	C_{oss}		Ch-1		120		
			Ch-2		180		
Reverse Transfer Capacitance	C_{rss}	Channel-2 $V_{DS} = 13 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$	Ch-1		55	nC	
			Ch-2		70		
Total Gate Charge	Q_g	$V_{DS} = 13 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 7 \text{ A}$	Ch-1		12	nC	
		$V_{DS} = 13 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 7 \text{ A}$	Ch-2		12		
Gate-Source Charge	Q_{gs}	Channel-1 $V_{DS} = 13 \text{ V}, V_{GS} = 4.5 \text{ V}, I_D = 7 \text{ A}$	Ch-1		5.5	nC	
			Ch-2		5.5		
		Channel-2 $V_{DS} = 13 \text{ V}, V_{GS} = 4.5 \text{ V}, I_D = 7 \text{ A}$	Ch-1		2		
			Ch-2		2		
Gate-Drain Charge	Q_{gd}	$f = 1 \text{ MHz}$	Ch-1		1.5	Ω	
			Ch-2		1.5		
Gate Resistance	R_g	$f = 1 \text{ MHz}$	Ch-1		2.5	Ω	
			Ch-2		2.5		

Notes:

a. Guaranteed by design, not subject to production testing.

b. Pulse test; pulse width $\leq 300 \mu\text{s}$, duty cycle $\leq 2\%$.



New Product

Si4670DY

Vishay Siliconix

SPECIFICATIONS $T_J = 25^\circ\text{C}$, unless otherwise noted

Parameter	Symbol	Test Conditions	Min	Typ ^a	Max	Unit
Dynamic^a						
Turn-On Delay Time	$t_{d(on)}$	Channel-1 $V_{DD} = 13 \text{ V}$, $R_L = 2.3 \Omega$ $I_D \geq 5.6 \text{ A}$, $V_{GEN} = 4.5 \text{ V}$, $R_g = 1 \Omega$	Ch-1	15	25	ns
Rise Time	t_r		Ch-2	15	25	
Turn-Off Delay Time	$t_{d(off)}$		Ch-1	50	75	
Fall Time	t_f		Ch-2	50	75	
Turn-On Delay Time	$t_{d(on)}$		Ch-1	20	30	
Rise Time	t_r		Ch-2	20	30	
Turn-Off Delay Time	$t_{d(off)}$		Ch-1	10	15	
Fall Time	t_f		Ch-2	10	15	
Drain-Source Body Diode Characteristics						
Continuous Source-Drain Diode Current	I_S	$T_C = 25^\circ\text{C}$	Ch-1		2.3	A
Pulse Diode Forward Current ^a	I_{SM}		Ch-2		2.3	
Body Diode Voltage	V_{SD}	$I_S = 5.6 \text{ A}$	Ch-1		30	V
Body Diode Reverse Recovery Time	t_{rr}	$I_S = 1 \text{ A}$	Ch-2		30	
Body Diode Reverse Recovery Charge	Q_{rr}	$I_F = 5.6 \text{ A}$, $\text{di}/\text{dt} = 100 \text{ A}/\mu\text{s}$, $T_J = 25^\circ\text{C}$	Ch-1	15	30	ns
Reverse Recovery Fall Time	t_a		Ch-2	15	30	
Reverse Recovery Rise Time	t_b		Ch-1	8	16	nC
			Ch-2	8	16	

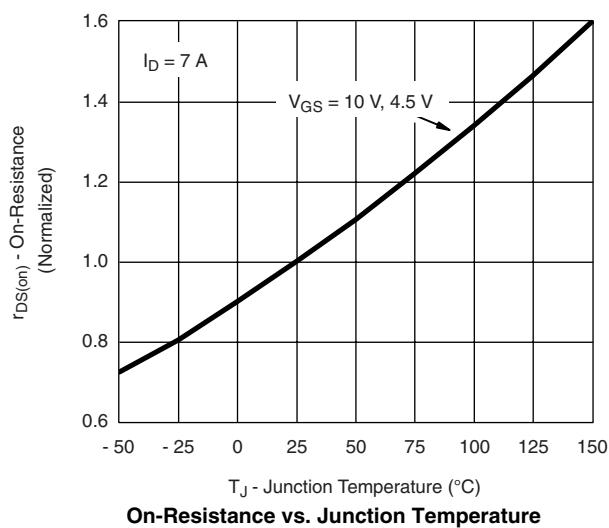
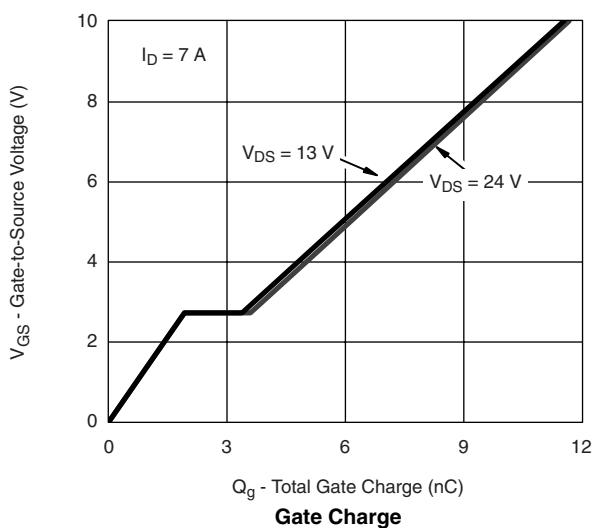
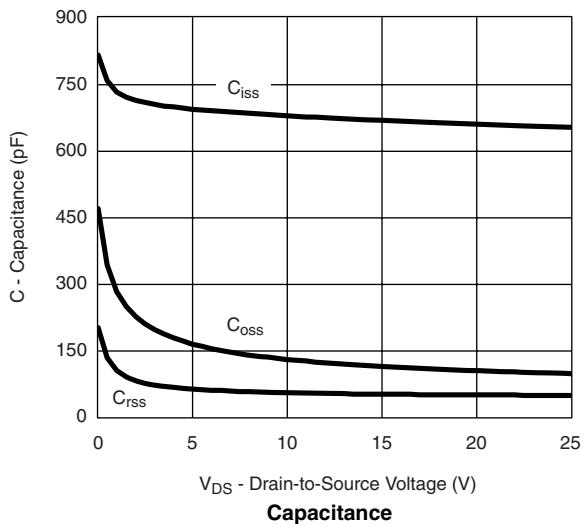
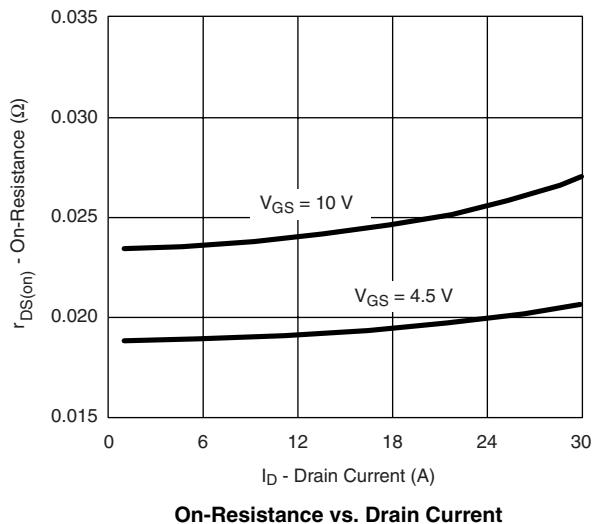
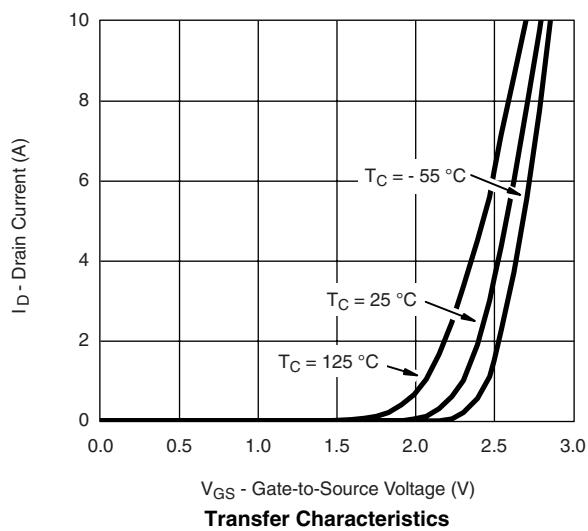
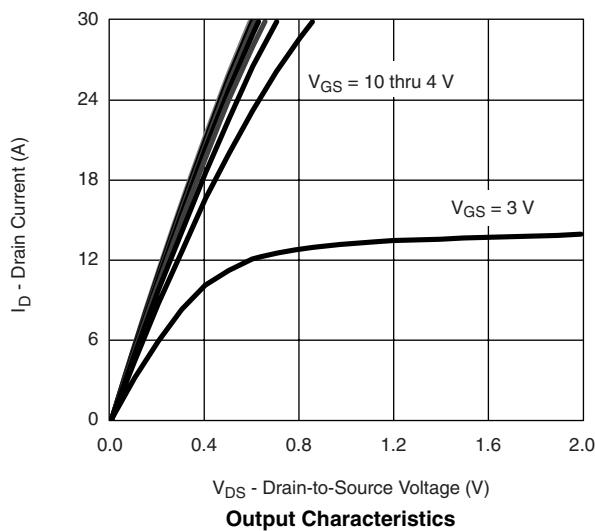
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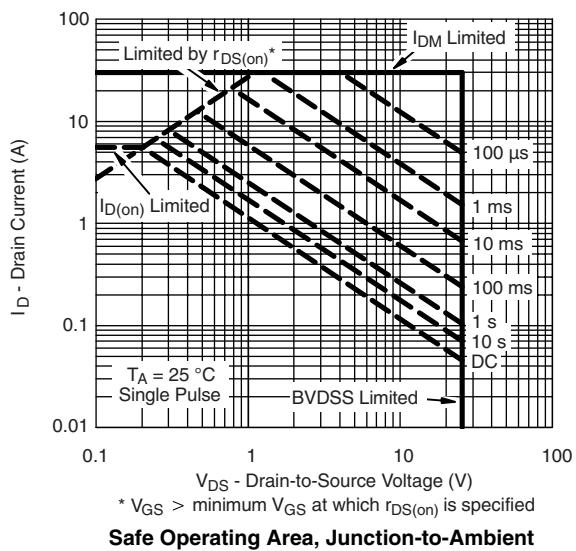
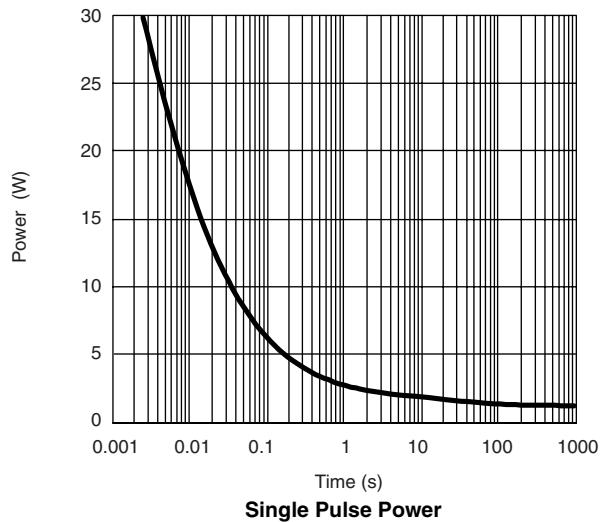
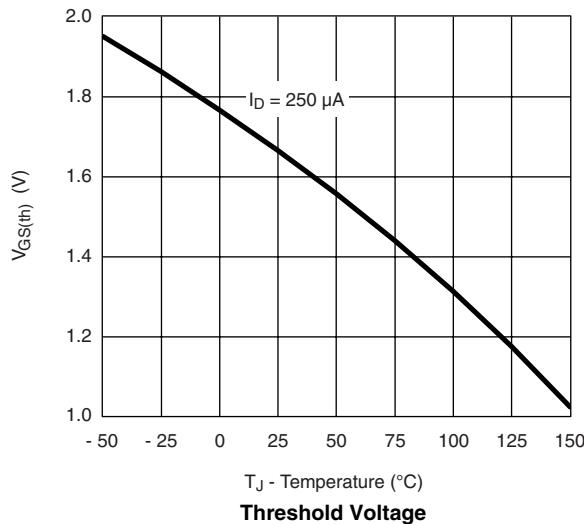
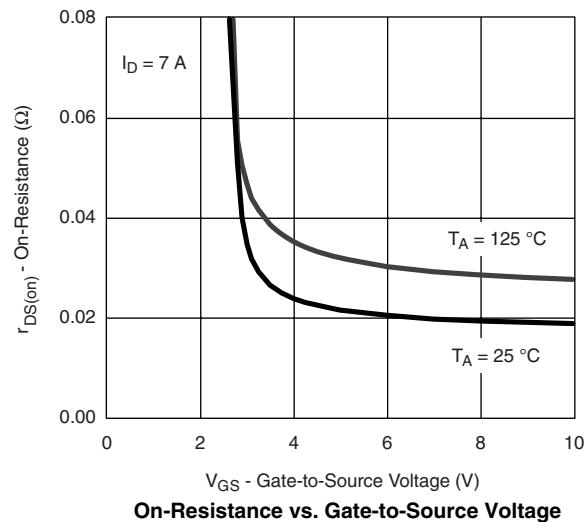
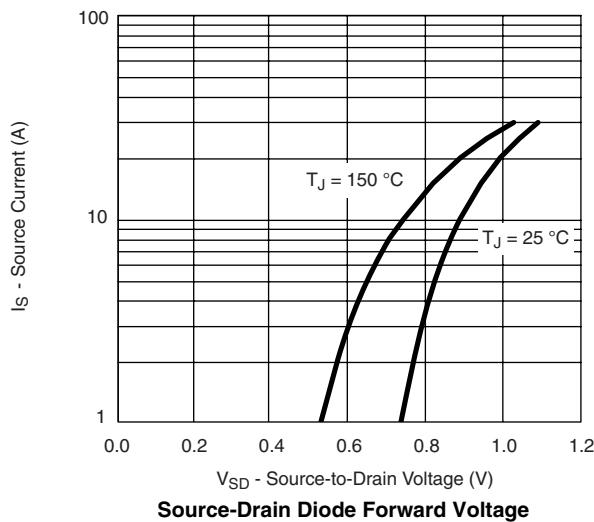
- a. Guaranteed by design, not subject to production testing.
- b. Pulse test; pulse width $\leq 300 \mu\text{s}$, duty cycle $\leq 2\%$.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

Si4670DY

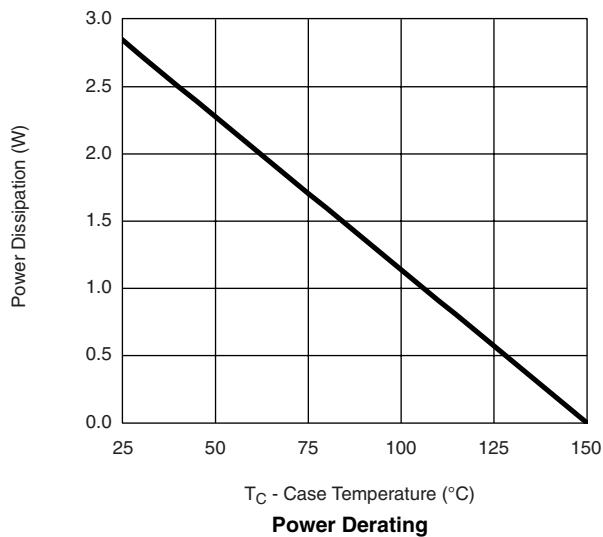
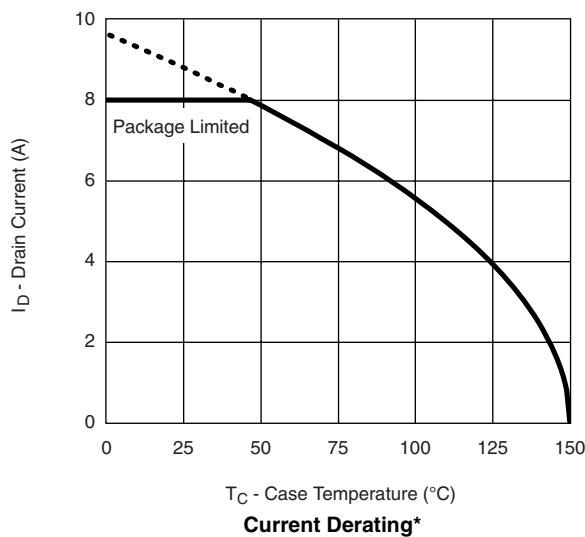
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**CHANNEL-1 TYPICAL CHARACTERISTICS** 25 °C, unless otherwise noted

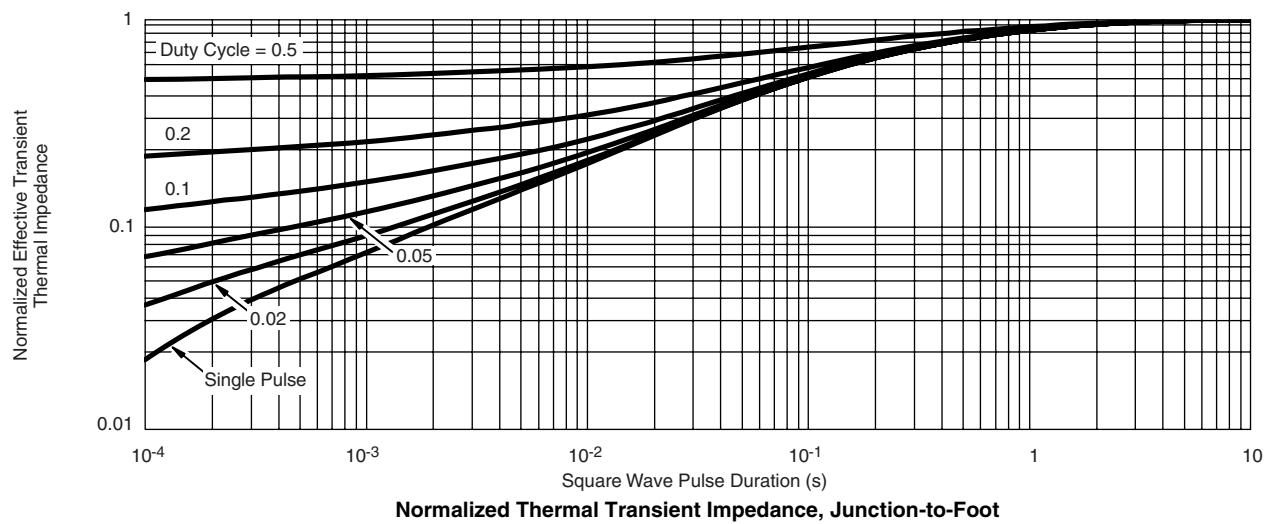
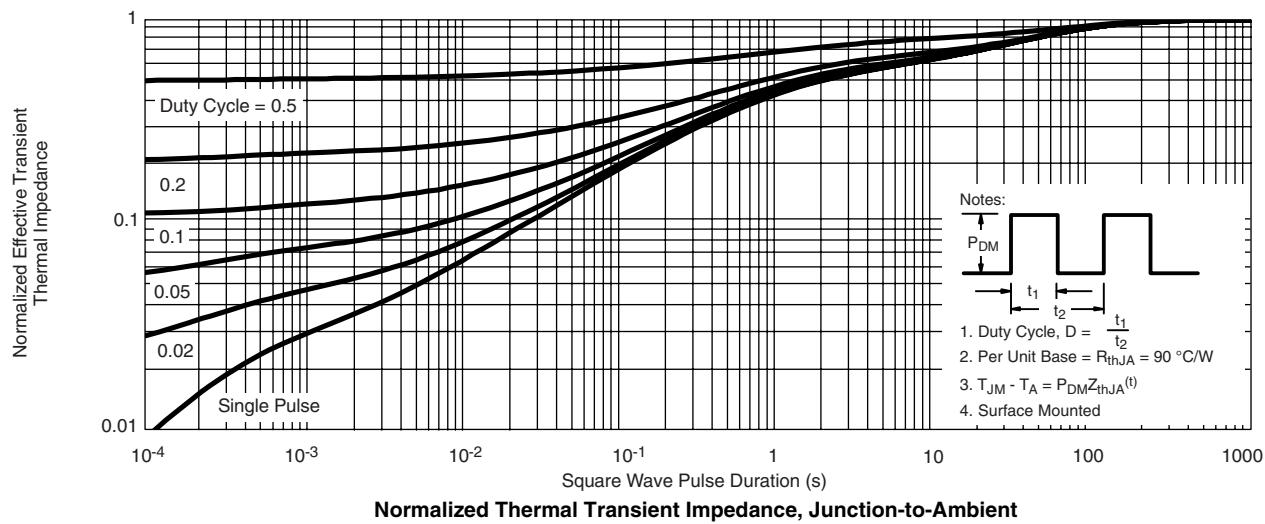
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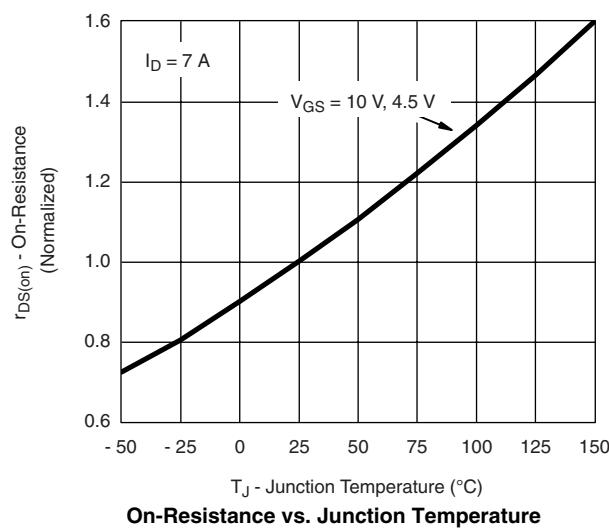
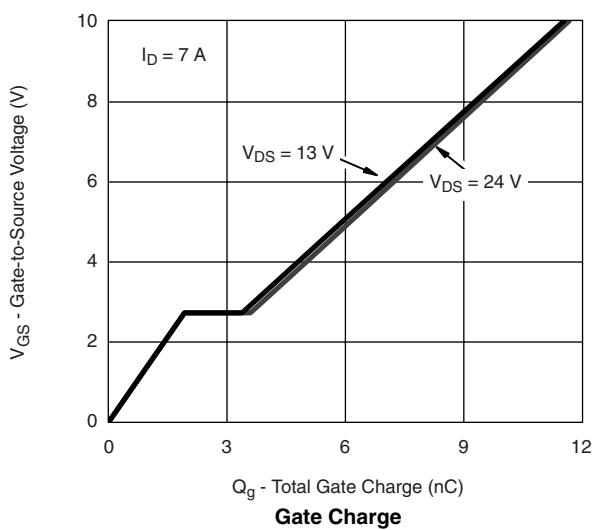
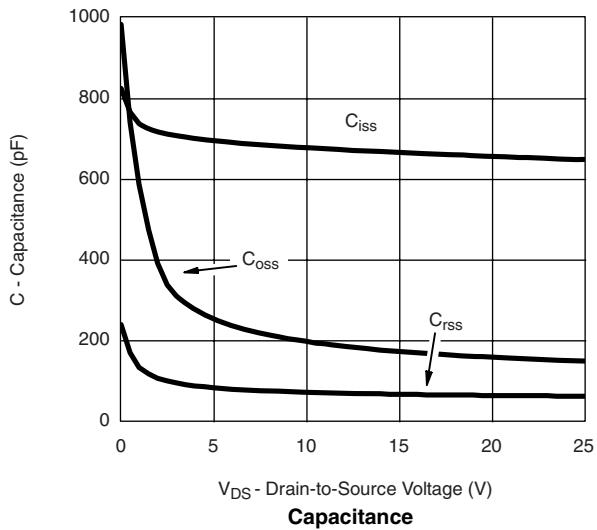
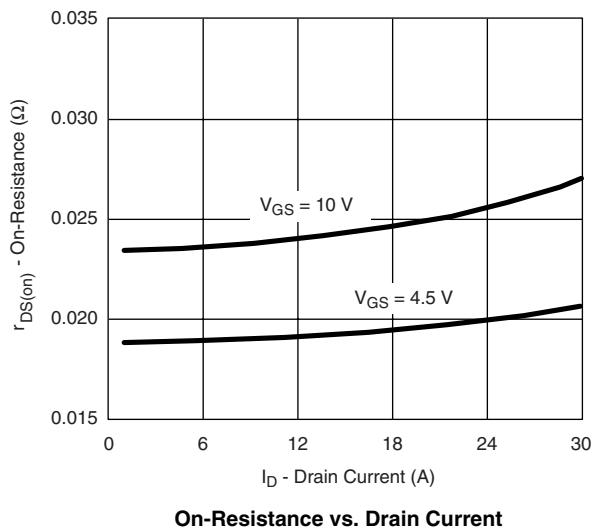
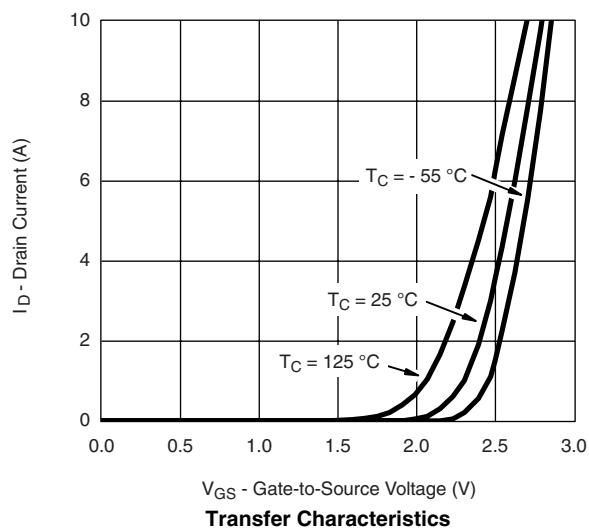
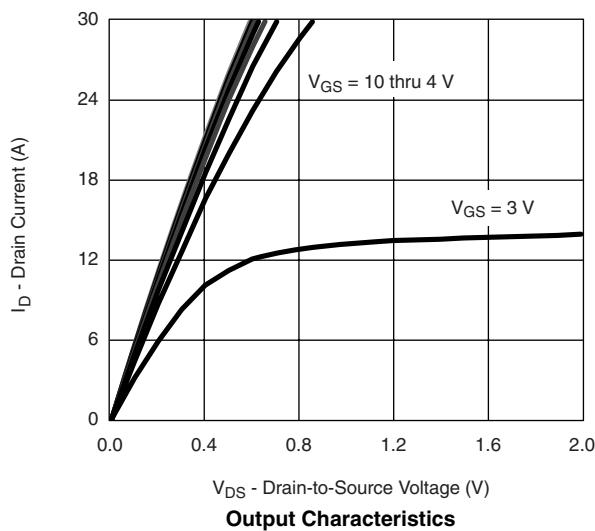
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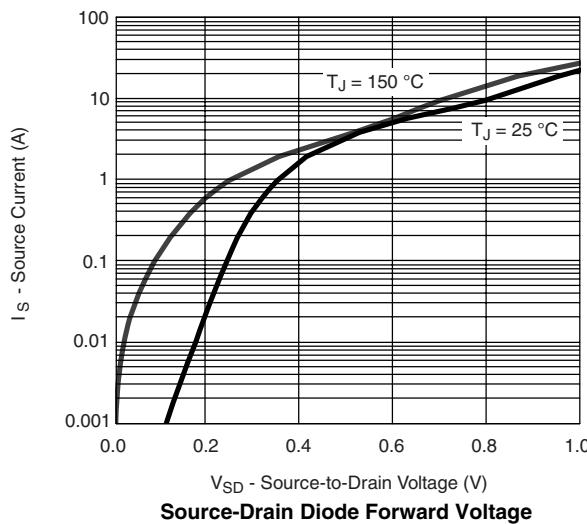
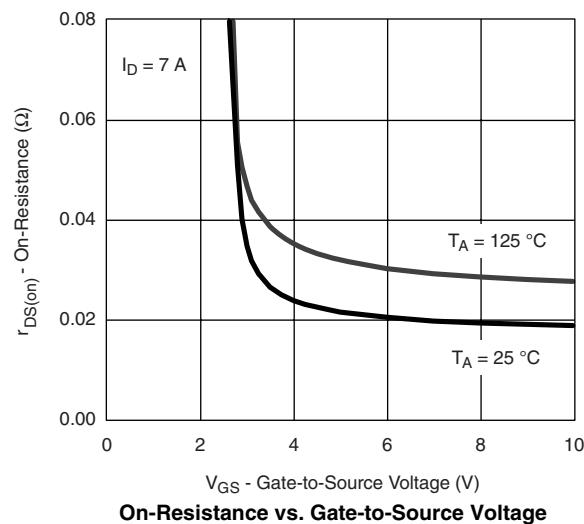
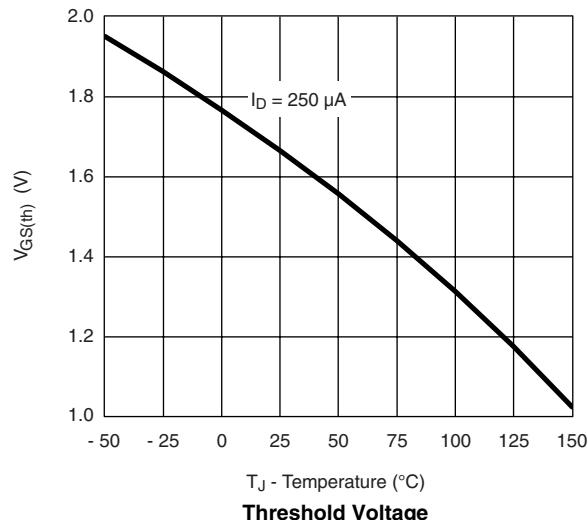
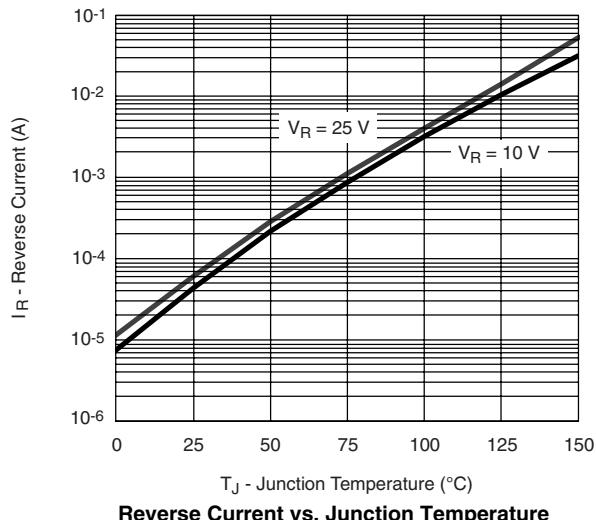
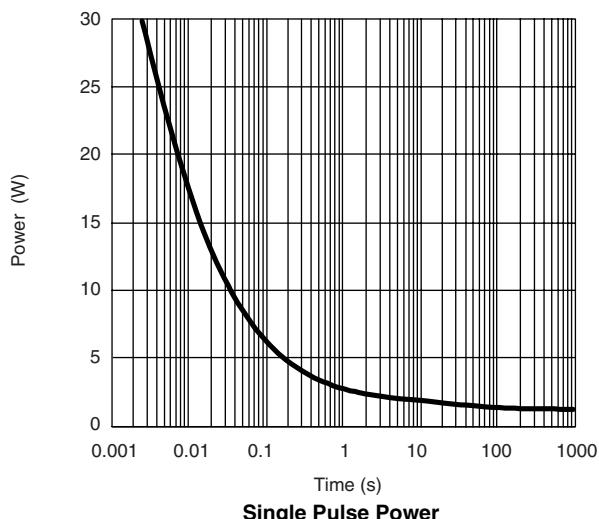
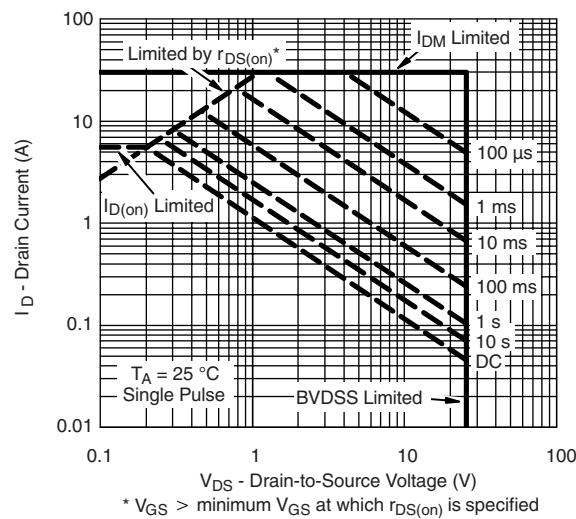
* The power dissipation P_D is based on $T_{J(\max)} = 150$ °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.

CHANNEL-1 TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted


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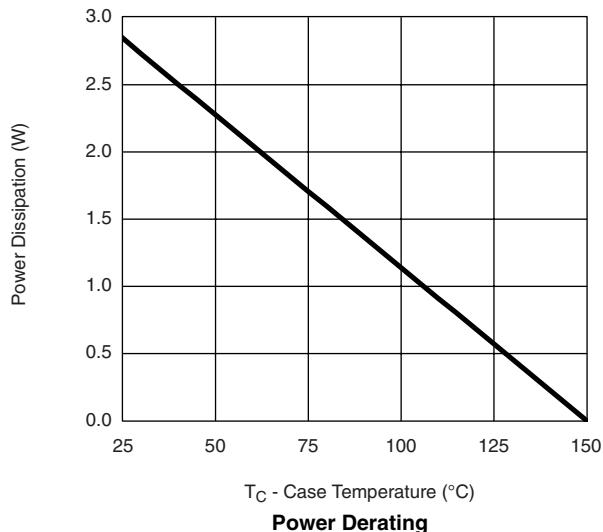
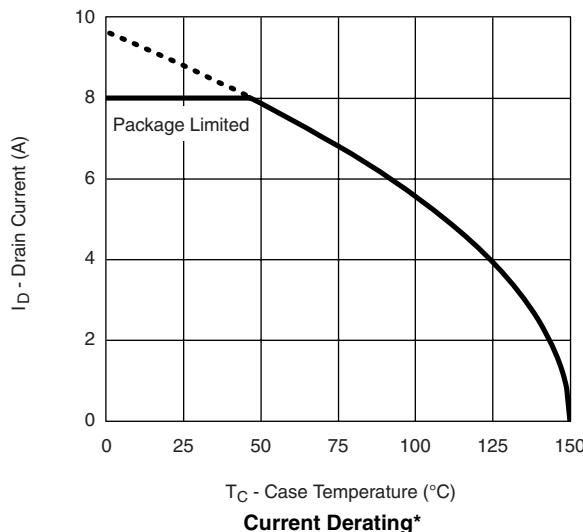
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**CHANNEL-2 TYPICAL CHARACTERISTICS** 25 °C, unless otherwise noted

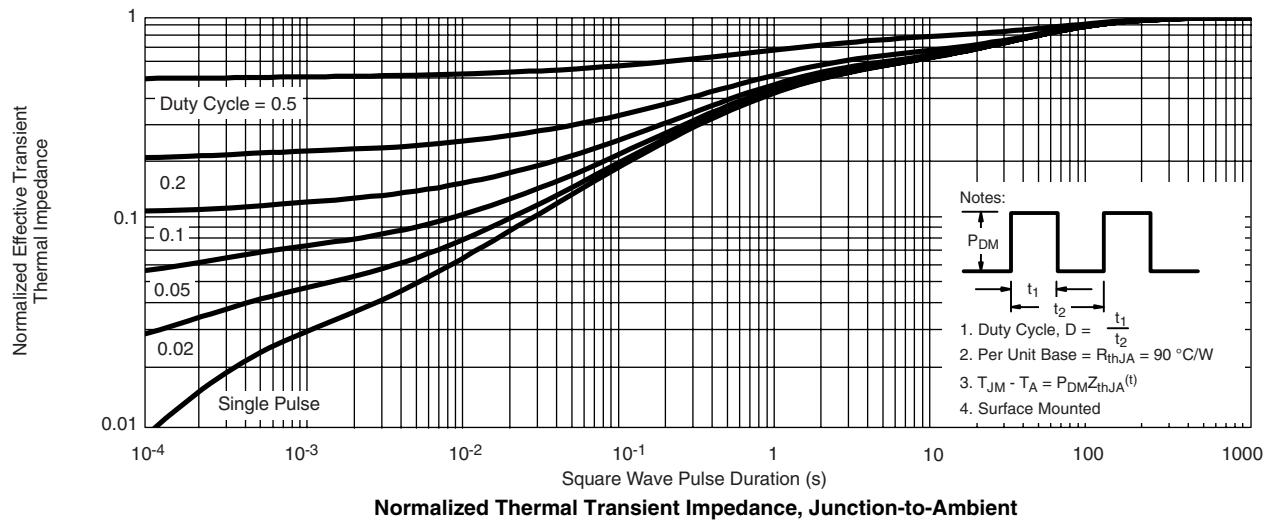
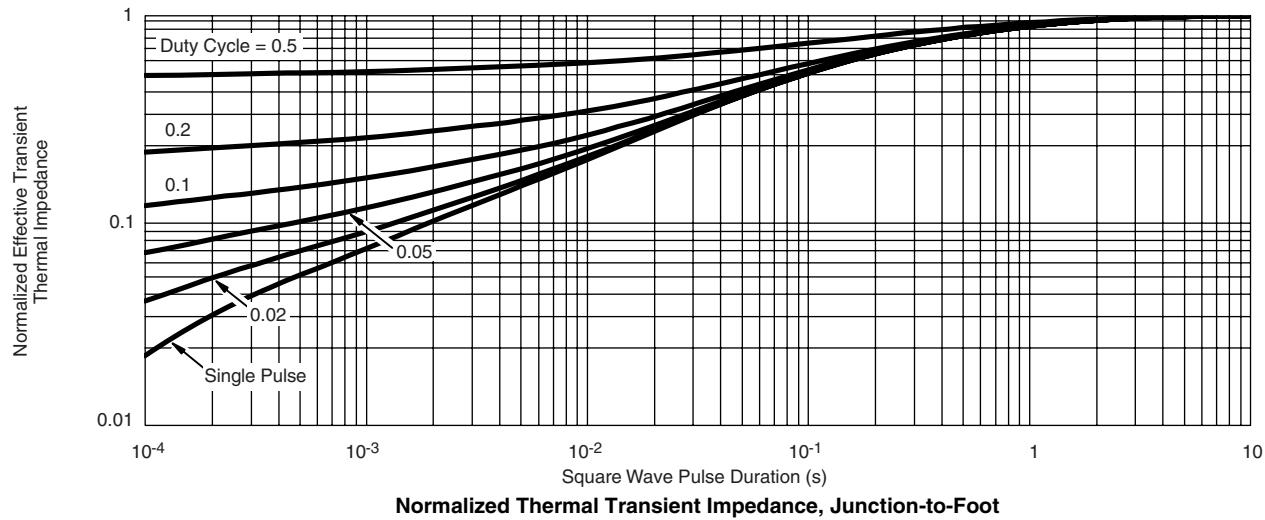
CHANNEL-2 TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

Source-Drain Diode Forward Voltage

On-Resistance vs. Gate-to-Source Voltage

Threshold Voltage

Reverse Current vs. Junction Temperature

Single Pulse Power

Safe Operating Area, Junction-to-Ambient

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**CHANNEL-2 TYPICAL CHARACTERISTICS** 25 °C, unless otherwise noted

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CHANNEL-2 TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

Normalized Thermal Transient Impedance, Junction-to-Ambient

Normalized Thermal Transient Impedance, Junction-to-Foot

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